## WEST

	Help Logout	09/855,609	
Main Menu	Search Form Posting Counts Show S Numbers	Edit S Numbers	Preferences Cases
**	Search Results -		
	Terms	Documents	
	L1 and (TMAT or TDEAT)	0	
Database:	US Patents Full-Text Database US Pre-Grant Publication Full-Text Database JPO Abstracts Database EPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins		gununwannannannwan van
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	Recall Text Clear		

## Printable Copy Create Case

Search History

**Hit Count Set Name** Set Name Query result set side by side DB=USPT; PLUR=YES; OP=ADJ 0 L1 and (TMAT or TDEAT) L9 L9 <u>L8</u> L7 and (TMAT or TDEAT) 1 L8 stack? near2 (barrier) 51 <u>L7</u> L7 9 L6 L4 and copper L6 0 L5 L4 and serially L5 stacked near2 (barrier adj layer) and adhesion 13 L4 L4 <u>L3</u> L1 and(TDMAT or TDEAT or TiCl4) 0 <u>L3</u> L1 and (adhesion adj layer) and (TDMAT or TDEAT or TiCl4) 0 L2 L2 100 Ll stacked near2 (barrier adj layer) <u>L1</u>

DATE: Sunday, March 09, 2003

## END OF SEARCH HISTORY

2 of 2



**Generate Collection** 

Print

Search Results - Record(s) 1 through 1 of 1 returned.

1. Document ID: US 5942799 A

L8: Entry 1 of 1

File: USPT

Aug 24, 1999

US-PAT-NO: 5942799

DOCUMENT-IDENTIFIER: US 5942799 A

TITLE: Multilayer diffusion barriers



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Print

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Terms	Documents
L7 and (TMAT or TDEAT)	1

Display Format: TI

Change Format

Previous Page

Next Page



Generate Collection

Print

Search Results - Record(s) 1 through 9 of 9 returned.

1. Document ID: US 6407422 B1

L6: Entry 1 of 9 File: USPT

Jun 18, 2002

US-PAT-NO: 6407422

DOCUMENT-IDENTIFIER: US 6407422 B1

TITLE: Oxygen diffusion blocking semiconductor capacitor

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMIC Draw, Desc Image

2. Document ID: US 6379977 B1

L6: Entry 2 of 9 File: USPT

Apr 30, 2002

US-PAT-NO: 6379977

DOCUMENT-IDENTIFIER: US 6379977 B1

TITLE: Method of manufacturing ferroelectric memory device

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWIC Draw. Desc - Image

3. Document ID: US 6245667 B1

L6: Entry 3 of 9 File: USPT

Jun 12, 2001

US-PAT-NO: 6245667

DOCUMENT-IDENTIFIER: US 6245667 B1

TITLE: Method of forming via

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw, Desc Image

4. Document ID: US 6242808 B1

L6: Entry 4 of 9 File: USPT

Jun 5, 2001

US-PAT-NO: 6242808

DOCUMENT-IDENTIFIER: US 6242808 B1

TITLE: Semiconductor device with copper wiring and semiconductor

device manufacturing method

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Drawi Desc - Image

5. Document ID: US 6207268 B1

L6: Entry 5 of 9 File: USPT

Mar 27, 2001

US-PAT-NO: 6207268

DOCUMENT-IDENTIFIER: US 6207268 B1

TITLE: Transfer sheet, and pattern-forming method

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw, Desc Image

KWAC

6. Document ID: US 6140231 A

L6: Entry 6 of 9 File: USPT

Oct 31, 2000

US-PAT-NO: 6140231

DOCUMENT-IDENTIFIER: US 6140231 A

TITLE: Robust diffusion barrier for Cu metallization

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw. Desc | Image

7. Document ID: US 6016011 A

L6: Entry 7 of 9 File: USPT

Jan 18, 2000

US-PAT-NO: 6016011

DOCUMENT-IDENTIFIER: US 6016011 A

TITLE: Method and apparatus for a dual-inlaid damascene contact to

sensor

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

8. Document ID: US 5506449 A

L6: Entry 8 of 9

File: USPT

Apr 9, 1996

US-PAT-NO: 5506449

DOCUMENT-IDENTIFIER: US 5506449 A

TITLE: Interconnection structure for semiconductor integrated

circuit and manufacture of the same

Full Title Citation Front Review Classification Date Reference Sequences Attachments KWMC Drawi Desc Image

9. Document ID: US 5335138 A

L6: Entry 9 of 9

File: USPT

Aug 2, 1994

US-PAT-NO: 5335138

DOCUMENT-IDENTIFIER: US 5335138 A

TITLE: High dielectric constant capacitor and method of manufacture

	little	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	K
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Change Format **Display Format:** TI

> Previous Page Next Page

Generate Collection

Print

**Search Results -** Record(s) 1 through 10 of 13 returned.

1. Document ID: US 6407422 B1

L4: Entry 1 of 13 File: USPT

Jun 18, 2002

US-PAT-NO: 6407422

DOCUMENT-IDENTIFIER: US 6407422 B1

TITLE: Oxygen diffusion blocking semiconductor capacitor

Full Title Citation Front Review Classification Date Reference Sequences Attachments Drawi Desc Image

2. Document ID: US 6406802 B1

L4: Entry 2 of 13

File: USPT

Jun 18, 2002

US-PAT-NO: 6406802

DOCUMENT-IDENTIFIER: US 6406802 B1

TITLE: Organic electroluminescent color display

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

3. Document ID: US 6379977 B1

L4: Entry 3 of 13

File: USPT

Apr 30, 2002

US PAT NO: 6379977

DOCUMENT-IDENTIFIER: US 6379977 B1

TITLE: Method of manufacturing ferroelectric memory device

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

4. Document ID: US 6245667 B1

L4: Entry 4 of 13 File: USPT

Jun 12, 2001

US-PAT-NO: 6245667

DOCUMENT-IDENTIFIER: US 6245667 B1

TITLE: Method of forming via

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

5. Document ID: US 6242808 B1

L4: Entry 5 of 13

File: USPT

Jun 5, 2001

US-PAT-NO: 6242808

DOCUMENT-IDENTIFIER: US 6242808 B1

TITLE: Semiconductor device with copper wiring and semiconductor

device manufacturing method

Full Title Citation Front Review Classification Date Reference Sequences Attachments Drawi Desc - Image

6. Document ID: US 6228701 B1

L4: Entry 6 of 13

File: USPT

May 8, 2001

US-PAT-NO: 6228701

DOCUMENT-IDENTIFIER: US 6228701 B1

TITLE: Apparatus and method for minimizing diffusion in stacked

capacitors formed on silicon plugs

Full Title Citation Front Review Classification Date Reference Sequences Attachments Drawi Desc Image

7. Document ID: US 6207268 B1

L4: Entry 7 of 13

File: USPT

Mar 27, 2001

US-PAT-NO: 6207268

DOCUMENT-IDENTIFIER: US 6207268 B1

TITLE: Transfer sheet, and pattern-forming method

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

8. Document ID: US 6140231 A

L4: Entry 8 of 13

File: USPT

Oct 31, 2000

US-PAT-NO: 6140231

DOCUMENT-IDENTIFIER: US 6140231 A

TITLE: Robust diffusion barrier for Cu metallization

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

9. Document ID: US 6016011 A

L4: Entry 9 of 13

File: USPT

Jan 18, 2000

US-PAT-NO: 6016011

DOCUMENT-IDENTIFIER: US 6016011 A

TITLE: Method and apparatus for a dual-inlaid damascene contact to

sensor

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

10. Document ID: US 5506449 A

L4: Entry 10 of 13

File: USPT

Apr 9, 1996

US-PAT-NO: 5506449

DOCUMENT-IDENTIFIER: US 5506449 A

TITLE: Interconnection structure for semiconductor integrated

circuit and manufacture of the same

Full Title Citation Front Review Classification Date Reference Sequences Attachments Draw Desc Image

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Terms **Documents** stacked near2 (barrier adj layer) and adhesion 13

**Display Format:** TI

Change Format

Previous Page

Next Page